Application/Control No. 10/587,268	Applicant(s)/Patent Under Reexamination TAKAIWA ET AL.		
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U.S. PATENT DOCUMENTS

	Old FATEUR DE COMMENTO				
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0103950	06-2004	Iriguchi, Chiharu	141/002
*	В	US-6,538,823	03-2003	Kroupenkine et al.	359/665
*	С	US-2006/0007419	01-2006	Streefkerk et al.	355/053
*	D	US-2001/0055100	12-2001	Murakami, Eiichi	355/53
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	Т	US-			
	J	US-			
	к	US-			
	L	US-			
	м	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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	Р					
	Q					
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	Т					

NON DATENT DOCUMENTS

NON-PATENT DOCUMENTS		
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